Certificate of Analysis

IARM 153C

AISI 317L / UNS S31703

Certified Reference Material

Certified Values listed in wt.% with associated uncertainties

Al	**0.003** ± 0.001	**As**	**0.0061** ± 0.0009	**B**	**0.0009** ± 0.0003	**C**	**0.0225** ± 0.0009
Co	**0.251** ± 0.003	**Cr**	**18.22** ± 0.04	**Cu**	**0.442** ± 0.005	**Mn**	**1.60** ± 0.01
Mo	**3.00** ± 0.04	**N**	**0.086** ± 0.001	**Nb**	**0.015** ± 0.002	**Ni**	**11.10** ± 0.05
O	**0.006** ± 0.001	**P**	**0.0289** ± 0.0006	**S**	**0.0288** ± 0.0008	**Si**	**0.349** ± 0.009
Sn	**0.010** ± 0.001	**Ti**	**0.004** ± 0.001	**V**	**0.058** ± 0.003	**W**	**0.043** ± 0.003
Zr	**0.004** ± 0.002						

Indicative Values listed in ppm

Ca (26)	H (<10)	Pb (10)	Sb (20)	Se (<400)	Ta (60)	Zn (<10)

Description and Intended Use

This CRM may come in the form of a solid disc or chips. The intended use of this CRM may include, but is not limited to, the calibration of instruments and the validation of analytical methods.

Interpretation of Data

1. Certified values listed reflect analysis results submitted by qualified analytical laboratories using a combination of methods and instrumentation that emulate actual methods and instrumental techniques currently utilized in the analytical community, and are reported as wt% unless otherwise noted.
2. This material was tested using both the solid disks and chips prepared from individual sections of bar. The certified values are considered representative of the overall average composition of the material.
3. Any data reported and enclosed by a parentheses ( ) is a "best estimate" and is not certified. This data could not be quantified sufficiently for certification. It was, however, reported by enough laboratories to be considered as potentially present in the matrix of the material being examined.
4. "Provisional Certificate of Analysis" reports values that support a fully certified reference material; it also indicates that values may be in a continued process of statistical evaluation and are subject to change.
5. Chips are not certified for Oxygen analysis.

The following data and accompanying statements represent all pertinent information reported in the ILAP as it applies to the chemical characterization of this material.

	Al	As	B	C	Ca	Co	Cr	Cu	H	Mn	Mo	N	Nb	Ni	O	P
1	0.0006	0.0048	0.0003	0.02	0.0024	0.243	18.115	0.426	0.0006	1.561	2.856	0.081	0.0106	10.885	0.0039	0.0274
2	0.0019	0.0055	0.0004	0.0206	0.0026	0.2441	18.116	0.4276		1.567	2.92	0.083	0.013	11.004	0.004	0.0274
3	0.002	0.0055	0.00044	0.0213	0.0027	0.2451	18.18	0.439		1.587	2.957	0.0835	0.013	11.0242	0.0049	0.0276
4	0.002	0.006	0.0005	0.02139	0.0027	0.248	18.19	0.4423		1.5956	2.969	0.084	0.0138	11.069	0.0052	0.0277
5	0.003	0.0063	0.0006	0.0216		0.2485	18.19	0.443		1.598	2.971	0.0852	0.015	11.08	0.006	0.028
6	0.0034	0.0066	0.00069	0.0217		0.25	18.2035	0.4437		1.5983	2.978	0.0854	0.015	11.085	0.0065	0.0288
7	0.004	0.0078	0.0008	0.0222		0.2528	18.227	0.445		1.60	3.0153	0.0858	0.015	11.10	0.0067	0.029
8	0.004		0.0009	0.0226		0.253	18.23	0.4459		1.603	3.033	0.086	0.0154	11.102	0.0075	0.029
9	0.0041		0.0009	0.023		0.253	18.24	0.446		1.6057	3.035	0.0868	0.0156	11.1233		0.029
10	0.0043		0.001	0.023		0.253	18.2591	0.447		1.609	3.039	0.0876	0.016	11.14		0.0296
11	0.0044		0.0018	0.0232		0.254	18.273	0.4472		1.612	3.0403	0.0876	0.0164	11.18		0.03
12	0.0074		0.002	0.0238		0.2545	18.29	0.449		1.619	3.0559	0.0884	0.0206	11.183		0.0301
13				0.024		0.259	18.356			1.62	3.058	0.089		11.191		0.0302
14				0.026						1.639	3.09			11.253		0.0304
15																
Mean	0.003	0.0061	0.0009	0.0225	0.0026	0.251	18.22	0.442		1.6	3	0.086	0.015	11.1	0.006	0.0289
STDV.	0.002	0.001	0.0005	0.002	0.0001	0.005	0.07	0.007		0.02	0.06	0.002	0.002	0.09	0.001	0.001
Certified	**0.003**	**0.0061**	**0.0009**	**0.0225**	**(0.0026)**	**0.251**	**18.22**	**0.442**	**(<0.001)**	**1.60**	**3.00**	**0.086**	**0.015**	**11.10**	**0.006**	**0.0289**
95% C.I.	0.001	0.0009	0.0003	0.0009		0.003	0.04	0.005		0.01	0.04	0.001	0.002	0.05	0.001	0.0006
Methods	O,IM,I	O,IM,I,A	O,I	O,C	O,IM	X,O,I	X,W,O,I	X,O,I	F	X,O,I	X,O,I	O,F	X,O,I	X,O,I	F	X,O,I

	Pb	S	Sb	Se	Si	Sn	Ta	Ti	V	W	Zn	Zr				
1	0.00001	0.026	0.0011	0.001	0.318	0.0077	0.0023	0.0017	0.0471	0.0373	0.00001	0.001				
2	0.00003	0.027	0.0013	0.001	0.333	0.0079	0.0038	0.002	0.0505	0.038	0.0001	0.0016				
3	0.00004	0.0274	0.0014	0.031	0.3342	0.0087	0.0054	0.002	0.0554	0.04	0.0008	0.0019				
4	0.0004	0.0278	0.003	<0.0001	0.341	0.009	0.0079	0.002	0.0564	0.0404	<0.0001	0.0028				
5	0.0011	0.0281	<0.004	<0.0001	0.3432	0.009	0.0097	0.0025	0.0567	0.0426	<0.002	0.0039				
6	0.0016	0.0284			0.3445	0.01	<0.0001	0.004	0.0573	0.0434		0.0058				
7	0.002	0.0287			0.351	0.01	<0.0030	0.0045	0.058	0.044		0.0081				
8		0.029			0.3515	0.0101	<0.01	0.0053	0.058	0.0458						
9		0.0295			0.3536	0.0107		0.0054	0.058	0.0468						
10		0.03			0.3546	0.011		0.0056	0.0583	0.0473						
11		0.03			0.3554	0.0118			0.059	0.048						
12		0.0302			0.357	0.0127			0.06							
13		0.03035			0.368				0.0609							
14		0.0304			0.384				0.07							
15																
Mean	0.001	0.0288	0.002	0.01	0.349	0.01	0.006	0.004	0.058	0.043	0.0003	0.004				
STDV.	0.0008	0.001	0.0009	0.02	0.02	0.002	0.003	0.002	0.005	0.004	0.0004	0.003				
Certified	**(0.001)**	**0.0288**	**(0.002)**	**(<0.04)**	**0.349**	**0.010**	**(0.006)**	**0.004**	**0.058**	**0.043**	**(<0.001)**	**0.004**				
95% C.I.		0.0008			0.009	0.001		0.001	0.003	0.003		0.002				
Methods	O,IM,A	O,C	O,IM,A	O,IM,A	X,O,I	O,IM,I,A	X,O,IM,I	X,O,IM,I	X,O,I	X,O,I	O,IM,A	X,O,IM,I				

Legend: W = Classical, C = Combustion, F = Fusion, A = AA or GFAA, I = ICP or DCP, IM=ICP-MS, D = DC Arc, O = AES, X = XRF, G = GDAES or GDMS, H = Hollow Cathode AES

Participating Laboratories

Certified Alloy Products, Inc.	Long Beach, CA	Element - Huntington Beach	Huntington Beach, CA
Dirats Laboratories	Westfield, MA	Laboratory Testing, Inc.	Hatfield, PA
AADFW, Inc.	Euless, TX	Laboratorio Prove Materiali S. Marco srl	Schio, Italy
Ellwood National Steel	Irvine, PA	Davis Alloys Manufacturing, LLC	Sharpsville, PA
PM Kalco, Inc	Wheatland, PA	MetalTek International, Inc.	Waukesha, WI
Crucible Industries	Syracuse, NY	Microlab	TamilNadu, India

Traceability

Members of the "Inter-Laboratory Analysis Program" (ILAP) validate test methods and instrument performance utilizing SRMs, CRMs, and RMs produced by recognized Certifying Bodies. The specific SRMs, CRMs, and RMs applicable to the material covered by this certificate are:

ALPHA AR1650	ALPHA AR654	ALPHA AR661	ALPHA AR676	ALPHA AR881	ALPHA AR882	ALPHA AR890	ASTM 0341	ASTM 9941
ASTM 9942	BCS 346	BCS SS466	BCS SS474	BS 185A	BS 316C	BS 317L	BS 60C	BS 84J
CMSI 2155	CMSI 2160	IARM 153B	IARM 162C	IARM 163D	IARM 2C	IARM 35J	IARM 5E	IARM 5G
LECO 501-502	LECO 501-644	LECO 502-809	MBH 13X12535	NIST 1155	NIST 1155A	NIST 1185	NIST 3107	NIST 3109A
NIST 3110	NIST 3137	NIST 3149	NIST 3155	NIST 3163	NIST 3168A	NIST 3169	NIST 361	NIST 363
NIST 897-9	SS474							

Homogeneity and Uncertainty

"Uncertainty" values, as reported adjacent to certified concentration values, are based on a 95% Confidence Interval. These estimated uncertainties include the combined effects of method imprecision, material inhomogeneity, and any bias between methods. Homogeneity data from experimental XRF results are reflected in both the overall statistics and certified data. Homogeneity samples are selected by a systematic sampling procedure. The number of samples may be determined by equation 1, where N_{prod} is the number of units produced and N_{min} is the number of samples used for homogeneity testing. These samples are arranged in a simple randomized design such that each sample is analyzed multiple times by XRF. Homogeneity is also determined within sample using an applied version of ASTM E826. A single factor ANOVA is used to calculated uncertainty due to inhomogeneity (U_{hom}). Uncertainty of the material is calculated by equation 2, where H=U_{hom}, S= Standard deviation, t= t-value at 95% CI, and n= number of observations.

1. $$N_{min} = \max(10, \sqrt[3]{N_{prod}})$$

2. $$U_{CRM} = \frac{\sqrt{H^2 + S^2}}{\sqrt{n}} * t$$

The International Standards Organization (ISO) definitions, expressed in ISO Guide 30–1992 list the following:

Certifying Body: Any technically competent body (organization or firm, public or private) that issues a reference material certificate with the information detailed in ISO Guide 31. The only generally accepted certifying body in the United States for primary standards or Standard Reference Materials (SRM) is the U. S. Department of Commerce, National Institute of Standards & Technology (NIST), Gaithersburg, MD. All other certifying bodies in the United States produce Reference Materials (RM) or Certified Reference Materials (CRM).

Reference Material (RM): Material or substance, with one or more property values that are sufficiently homogeneous and well established, to be used for the calibration of an apparatus, the assessment of a measurement method, or for assigning values to materials.

Certified Reference Material (CRM): Reference material, accompanied by a certificate, with one or more property values certified by a procedure, which establishes its traceability to an accurate realization of the unit in which the property values are expressed, and for which each certified value is accompanied by an uncertainty at a stated level of confidence.

Inter-Laboratory Analysis Program (ILAP): ASTM Standard E691-87 applies to inter-laboratory studies to "Determine the Precision of a Single Test Method", but also outlines a well thought out and logical plan for conducting an inter laboratory program involving multiple analytical techniques. Therefore, the guidelines established in ASTM E691-87 were applied to all aspects of this inter laboratory program, including the protocols for planning, handling, analysis and treatment of resulting data.

Methods of Analysis: The "Inter Laboratory Analysis Program" analyzes a wide variety of materials, and as a result, no single analytical method would provide optimum analytical results. Therefore, a combination of ASTM Standard Methods for classical wet chemistry, ICP, AA, Optical Emission, X-Ray spectrometric, and other accepted methods were used to produce analytical data. Carbon, Sulfur, Nitrogen, and Oxygen results were supplied from combustion and OE instrument procedures.

Expiration of Certification: The certification of this IARM is valid indefinitely, within the uncertainty specified, provided the IARM is handled and stored in accordance with the instructions stated on this certificate. The certification is nullified if the IARM is damaged, contaminated, otherwise modified, or used in a manner for which it was not intended.

Instructions for Use: The test surface is on the side opposite to the labeled surface, which includes the IARM number. The entire thickness of the unit is certified. However, the user is cautioned not to measure disks less than 2 mm thick when using X-ray fluorescence spectrometry. Each packaged disk has been prepared by finishing the test surface using a lathe. The user must determine the correct surface preparation procedure for each analytical technique. The user is cautioned to use care when either resurfacing the disk or performing additional polishing, as these processes may contaminate the surface. The minimum sample size for chips should be individually evaluated based on the analytical technique used; this would typically be greater than 0.1 grams. The material should be stored in a cool, dry location when not in use. Chips are not to be used for Oxygen analysis.

Selection of Materials: A "batch" or "series" is defined as a continuous length of bar produced from a single heat. The majority of IARM materials are in wrought condition; other methods of manufacture are utilized if necessary. ILAP samples are removed from equal sections from the total length of the bar. A portion of each section is converted to chips and a thin (pin) disk for analysis by classical wet chemistry, ICP, AA, and combustion procedures, and the balance remains as a thick disk for OES and X-Ray analysis.

David Coler, General Manager

Analytical Reference Materials International